

Search Notes

Application/Control No.

10/010,672

Examiner

Brian E. Miller

Applicant(s)/Patent under
Reexamination

CHANG ET AL.

Art Unit

2652

SEARCHED

Class	Subclass	Date	Examiner
360	235.6		
360	235.8		
360	236		
360	236.3		
360	236.4		
360	236.6		
360	237	4/11/2005	BEM

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
360	235.8		
360	236.3	4/11/2005	BEM

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS Search	4/11/2005	BEM